

Form PTO 1449 (Modified)		U.S. DEPARTMENT O PATENT AND TRADE	204838US3 CONT				New Cont. Application			
LIST OF	PEFE	RENCES CITED BY APP	LICANT	APPLICANT Yukio KOHMURA						
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-			ı	J.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	NAME CLA			SUB CLASS	FILING DATE IF APPROPRIATE	
de	AA	4,726,764	2/23/88	Yoshikai			_			
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FOREIGN PATENT DOCUMENTS										
		DOCUMENT NUMBER	DATE	COUNTRY	Class		Sibsi	TRANSLATION YES NO		
a	AO	6-127964	5/10/94		7	~	1-		X	
	AP	4-21535	1/24/92	Japan (w/ English Abstract)	\bot		_		X	
	AQ	5-66092	3/19/93	L <u></u>	4		<u> </u>		X	
	AR	61-26531	 	Japan (w/ English Abstract)	1		1-		X	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)										
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*Examiner: Ini conformance a	Examiner: Initial of perence is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									